

### FEATURES

- Access Times of 120, 150, 200, and 250ns
- Single 5V±10% Power Supply
- Simple Byte and Page Write
- Low Power CMOS:
  - 60 mA Active Current
  - 500 µA Standby Current
- Fast Write Cycle Times
- Software Data Protection
- Fully TTL Compatible Inputs and Outputs
- Endurance:
  - 10,000 Cycles/byte
  - 100,000 Cycles/page
- Data Retention: 100 Years
- Available in the following package:
  - 32-Pin 600 mil Ceramic DIP
  - 32-Pin Ceramic LCC (450x550 mils)
  - 32-Pin Solder Seal Flatpack
  - 44-Pin Ceramic LCC (650x650 mils)



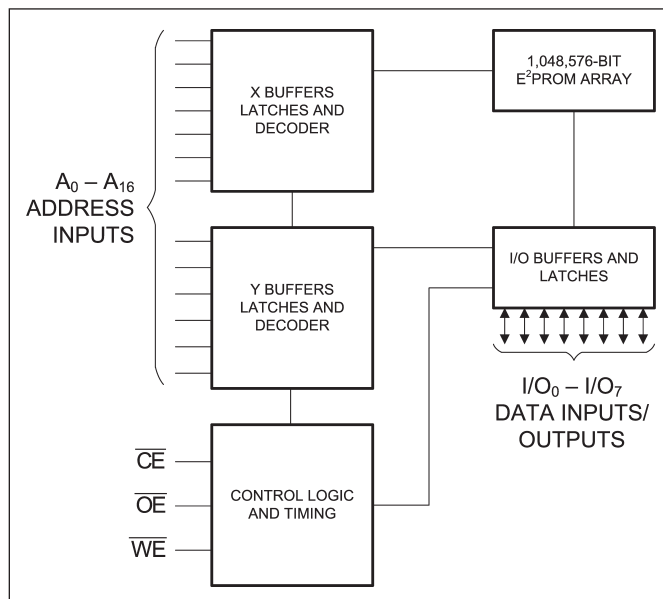
### DESCRIPTION

The PYA28C010 is a 5 Volt 128Kx8 EEPROM using floating gate CMOS Technology. The device supports 64-byte page write operation. The PYA28C010 features  $\overline{\text{DATA}}$  and Toggle Bit Polling as well as a system software scheme

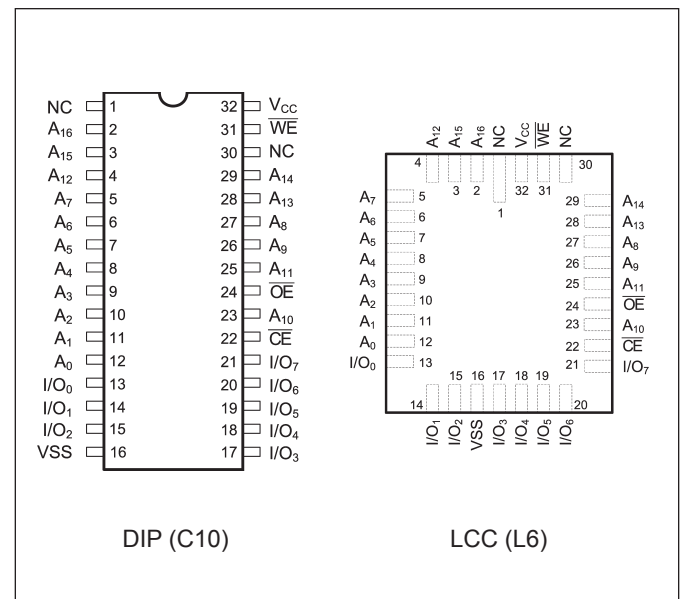
used to indicate early completion of a Write Cycle. The device also includes user-optional software data protection. Data Retention is 100 Years. The device is available in a 32-Pin 600 mil wide Ceramic DIP, 32-Pin LCC, 32-Pin Solder Seal Flatpack and 44-Pin Ceramic LCC.



### FUNCTIONAL BLOCK DIAGRAM



### PIN CONFIGURATION





## OPERATION

### READ

Read operations are initiated by both  $\overline{OE}$  and  $\overline{CE}$  LOW. The read operation is terminated by either  $\overline{CE}$  or  $\overline{OE}$  returning HIGH. This two line control architecture eliminates bus contention in a system environment. The data bus will be in a high impedance state when either  $\overline{OE}$  or  $\overline{CE}$  is HIGH.

### WRITE

Write operations are initiated when both  $\overline{CE}$  and  $\overline{WE}$  are LOW and  $\overline{OE}$  is HIGH. The PYA28C010 supports both a  $\overline{CE}$  and  $\overline{WE}$  controlled write cycle. That is, the address is latched by the falling edge of either  $\overline{CE}$  or  $\overline{WE}$ , whichever occurs last. Similarly, the data is latched internally by the rising edge of either  $\overline{CE}$  or  $\overline{WE}$ , whichever occurs first. A byte write operation, once initiated, will automatically continue to completion, typically within 5 ms.

### PAGE WRITE

The page write feature of the AS28C010 allows the entire memory to be written in 5 seconds. Page write allows two to two hundred fifty-six bytes of data to be consecutively written to the PYA28C010 prior to the commencement of the internal programming cycle. The host can fetch data from another device within the system during a page write operation (change the source address), but the page address ( $A_8$  through  $A_{16}$ ) for each subsequent valid write cycle to the part during this operation must be the same as the initial page address.

The page write mode can be initiated during any write operation. Following the initial byte write cycle, the host can write an additional one to two hundred fifty-six bytes in the same manner as the first byte was written. Each successive byte load cycle, started by the  $\overline{WE}$  HIGH to LOW transition, must begin within 100 $\mu$ s of the falling edge of the preceding  $\overline{WE}$ . If a subsequent  $\overline{WE}$  HIGH to LOW transition is not detected within 100 $\mu$ s, the internal automatic programming cycle will commence. There is no page write window limitation. Effectively the page write window is infinitely wide, so long as the host continues to access the device within the byte load cycle time of 100 $\mu$ s.

### WRITE

The PYA28C010 provides the user two write operation status bits. These can be used to optimize a system write cycle time. The status bits are mapped onto the I/O bus as shown below.



### DATA POLLING

The PYA28C010 features  $\overline{DATA}$  Polling as a method to indicate to the host system that the byte write or page write cycle has completed.  $\overline{DATA}$  Polling allows a simple bit test operation to determine the status of the PYA28C010, eliminating additional interrupts or external hardware. During the internal programming cycle, any attempt to read the last byte written will produce the complement of that data on  $I/O_7$  (i.e., write data=0xxx xxxx, read data=1xxx xxxx). Once the programming cycle is complete,  $I/O_7$  will reflect true data. Note: If the PYA28C010 is in the protected state and an illegal write operation is attempted,  $\overline{DATA}$  Polling will not operate.

### TOGGLE BIT

The PYA28C010 also provides another method for determining when the internal write cycle is complete. During the internal programming cycle,  $I/O_6$  will toggle from HIGH to LOW and LOW to HIGH on subsequent attempts to read the device. When the internal cycle is complete the toggling will cease and the device will be accessible for additional read or write operations.

**MAXIMUM RATINGS<sup>(1)</sup>**

Sym	Parameter	Value	Unit
V <sub>CC</sub>	Power Supply Pin with Respect to GND	-0.3 to +6.25	V
V <sub>TERM</sub>	Terminal Voltage with Respect to GND (up to 6.25V)	-0.5 to +6.25	V
T <sub>A</sub>	Operating Temperature	-55 to +125	°C
T <sub>BIAS</sub>	Temperature Under Bias	-55 to +125	°C
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
P <sub>T</sub>	Power Dissipation	1.0	W
I <sub>OUT</sub>	DC Output Current	50	mA

**RECOMMENDED OPERATING CONDITIONS**

Grade <sup>(2)</sup>	Ambient Temp	GND	V <sub>CC</sub>
Military	-55°C to +125°C	0V	5.0V ± 10%

**CAPACITANCES<sup>(4)</sup>**(V<sub>CC</sub> = 5.0V, T<sub>A</sub> = 25°C, f = 1.0MHz)

Sym	Parameter	Conditions	Typ	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	10	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	10	pF

**DC ELECTRICAL CHARACTERISTICS**(Over Recommended Operating Temperature & Supply Voltage)<sup>(2)</sup>

Sym	Parameter	Test Conditions	PYA28C010		Unit
			Min	Max	
V <sub>IH</sub>	Input High Voltage		2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage		-0.5 <sup>(3)</sup>	0.8	V
V <sub>HC</sub>	CMOS Input High Voltage		V <sub>CC</sub> - 0.2	V <sub>CC</sub> + 0.5	V
V <sub>LC</sub>	CMOS Input Low Voltage		-0.5 <sup>(3)</sup>	0.2	V
V <sub>OL</sub>	Output Low Voltage (TTL Load)	I <sub>OL</sub> = +2.1 mA, V <sub>CC</sub> = Min		0.4	V
V <sub>OH</sub>	Output High Voltage (TTL Load)	I <sub>OH</sub> = -0.4 mA, V <sub>CC</sub> = Min	2.4		V
I <sub>LI</sub>	Input Leakage Current	V <sub>CC</sub> = Max V <sub>IN</sub> = GND to V <sub>CC</sub>	-10	+10	µA
I <sub>LO</sub>	Output Leakage Current	V <sub>CC</sub> = Max, $\overline{CE} = V_{IH}$ V <sub>OUT</sub> = GND to V <sub>CC</sub>	-10	+10	µA
I <sub>SB</sub>	Standby Power Supply Current (TTL Input Levels)	$\overline{CE} \geq V_{IH}$ , $\overline{OE} = V_{IL}$ V <sub>CC</sub> = Max, f = Max, Outputs Open	—	3	mA
I <sub>SB1</sub>	Standby Power Supply Current (CMOS Input Levels)	$\overline{CE} \geq V_{HC}$ V <sub>CC</sub> = Max, f = Max, Outputs Open, V <sub>IN</sub> ≤ V <sub>LC</sub> or V <sub>IN</sub> ≥ V <sub>HC</sub>	—	500	µA
I <sub>CC</sub>	Supply Current	$\overline{CE} = \overline{OE} = V_{IL}$ $\overline{WE} = V_{IH}$ All I/O's = Open, Inputs = V <sub>CC</sub> = 5.5V	—	60	µA

**Notes:**

- Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to MAXIMUM rating conditions for extended periods may affect reliability.
- Extended temperature operation guaranteed with 400 linear feet per minute of air flow.
- Transient inputs with V<sub>IL</sub> and I<sub>IL</sub> not more negative than -3.0V and -100mA, respectively, are permissible for pulse widths up to 20ns.
- This parameter is sampled and not 100% tested.



## POWER-UP TIMING

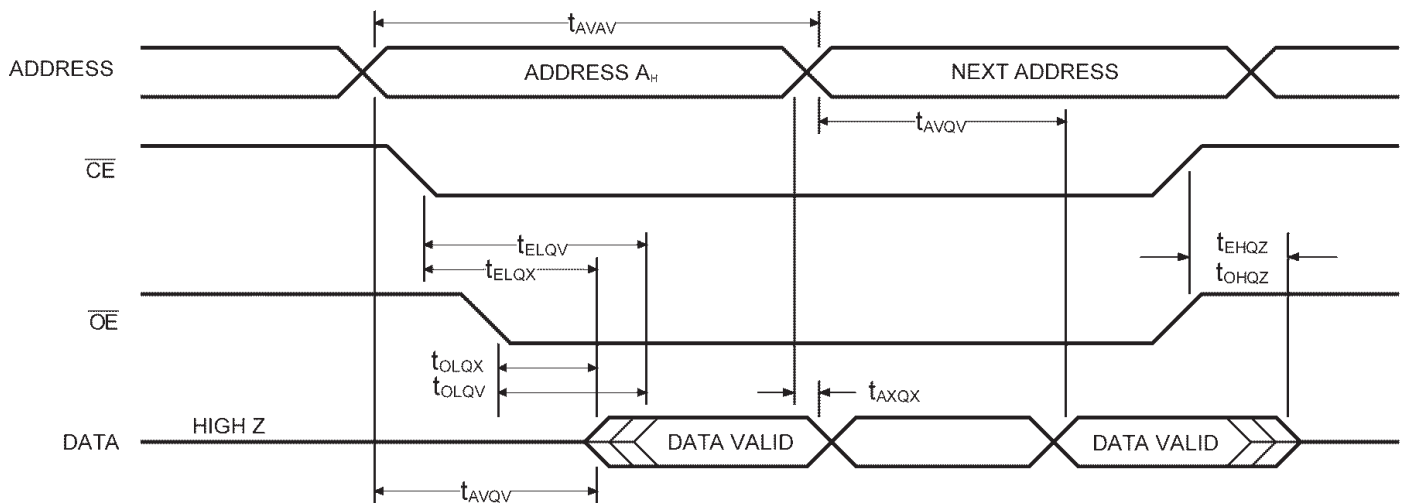
Symbol	Parameter	Max	Unit
$t_{PUR}$	Power-up to Read operation	100	$\mu$ s
$t_{PUW}$	Power-up to Write operation	5	ms

## AC ELECTRICAL CHARACTERISTICS—READ CYCLE

( $V_{CC} = 5V \pm 10\%$ , All Temperature Ranges)<sup>(2)</sup>

Sym	Parameter	-120		-150		-200		-250		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
$t_{AVAV}$	Read Cycle Time	120		150		200		250		ns
$t_{AVQV}$	Address Access Time		120		150		200		250	ns
$t_{ELQV}$	Chip Enable Access Time		120		150		200		250	ns
$t_{OLQV}$	Output Enable Access Time		50		50		50		50	ns
$t_{ELQX}$	Chip Enable to Output in Low Z	0		0		0		0		ns
$t_{EHQZ}$	Chip Disable to to Output in High Z		50		50		50		50	ns
$t_{OLQX}$	Output Enable to Output in Low Z	0		0		0		0		ns
$t_{OHQZ}$	Output Disable to Output in High Z		50		50		50		50	ns
$t_{AVQX}$	Output Hold from Address Change	0		0		0		0		ns

## TIMING WAVEFORM OF READ CYCLE





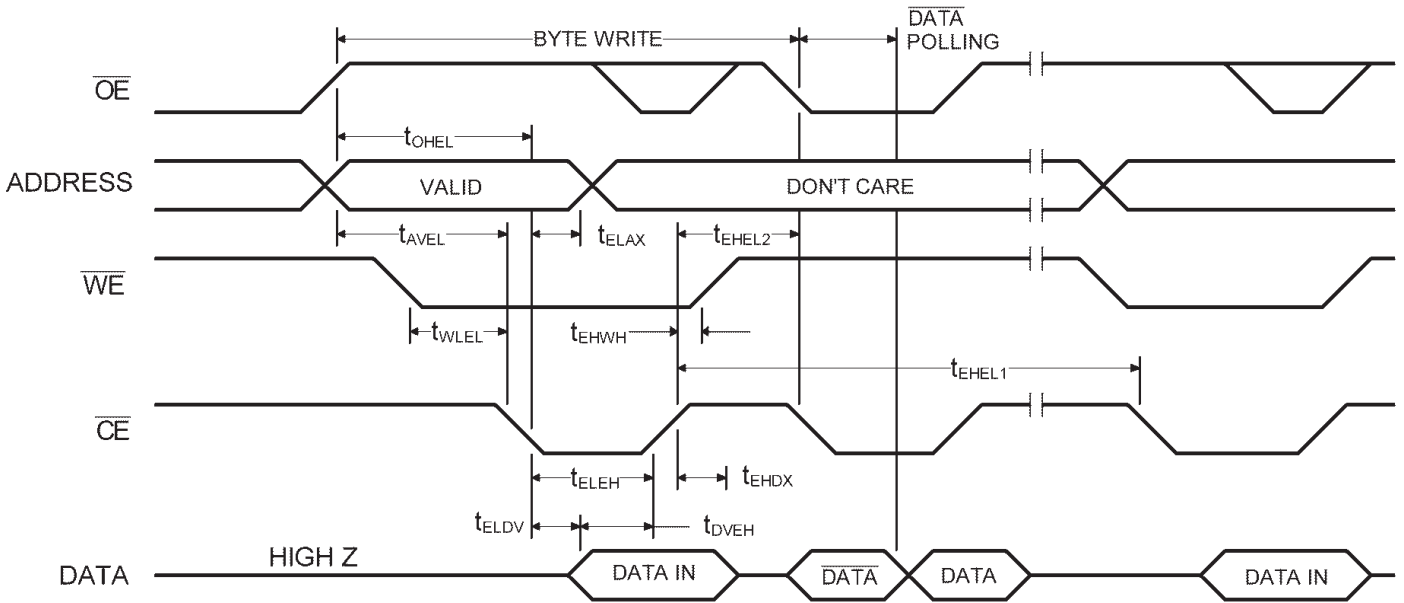
## AC CHARACTERISTICS—WRITE CYCLE

( $V_{CC} = 5V \pm 10\%$ , All Temperature Ranges)<sup>(2)</sup>

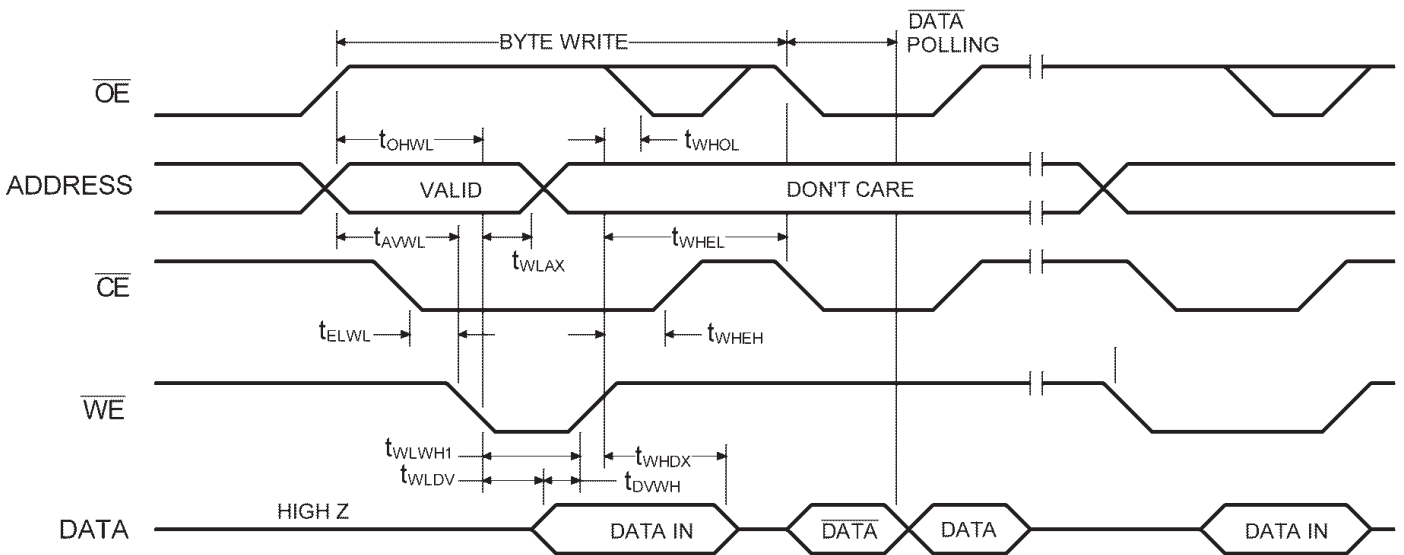
Symbol	Parameter	-120		-150		-200		-250		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
$t_{WHWL1}$ $t_{EH1}$	Write Cycle Time		10		10		10		10	ms
$t_{AVEL}$ $t_{AVWL}$	Address Setup Time	0		0		0		0		ns
$t_{ELAX}$ $t_{WLAX}$	Address Hold Time	50		50		50		50		ns
$t_{WLEL}$ $t_{ELWL}$	Write Setup Time	0		0		0		0		ns
$t_{WHEH}$	Write Hold Time	0		0		0		0		ns
$t_{OH1}$ $t_{OH1}$	$\overline{OE}$ Setup Time	10		10		10		10		ns
$t_{WHOL}$	$\overline{OE}$ Hold Time	10		10		10		10		ns
$t_{ELEH}$ $t_{WLWH}$	$\overline{WE}$ Pulse Width	100		100		100		100		ns
$t_{DVEH}$ $t_{DVWH}$	Data Setup Time	50		50		50		50		ns
$t_{EHD1}$ $t_{WHDX}$	Data Hold Time	0		0		0		0		ns
$t_{EH1}$ $t_{WH1}$	Byte Load Cycle Time	0.2	100	0.2	100	0.2	100	0.2	100	$\mu$ s
$t_{ELWL}$	$\overline{CE}$ Setup Time	1		1		1		1		$\mu$ s
$t_{OVH1}$	Output Setup Time	1		1		1		1		$\mu$ s
$t_{EH1}$	$\overline{CE}$ Hold Time	1		1		1		1		$\mu$ s
$t_{WH1}$	$\overline{OE}$ Hold Time	1		1		1		1		$\mu$ s



### TIMING WAVEFORM OF BYTE WRITE CYCLE ( $\overline{CE}$ CONTROLLED)



### TIMING WAVEFORM OF BYTE WRITE CYCLE ( $\overline{WE}$ CONTROLLED)

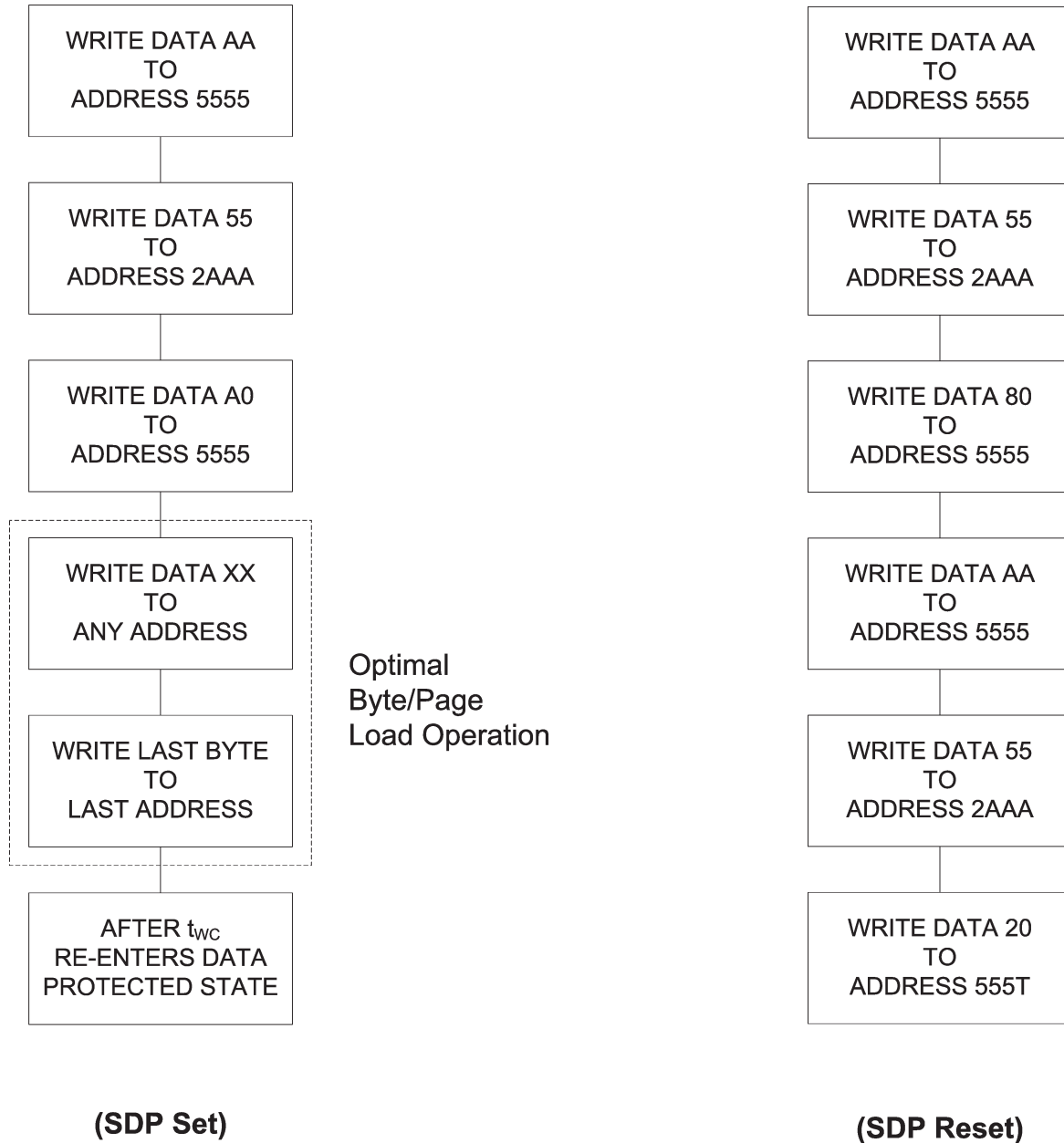






## WRITE SEQUENCE FOR SOFTWARE DATA PROTECTION

## SOFTWARE SEQUENCE TO DE-ACTIVATE SOFTWARE DATA PROTECTION





### AC TEST CONDITIONS

Input Pulse Levels	GND to 3.0V
Input Rise and Fall Times	10ns
Input Timing Reference Level	1.5V
Output Timing Reference Level	1.5V
Output Load	See Figure 1

### TRUTH TABLE

Mode	$\overline{CE}$	$\overline{OE}$	$\overline{WE}$	I/O
Read	L	L	H	D <sub>OUT</sub>
Write	L	H	L	D <sub>IN</sub>
Write Inhibit	X	L	X	—
Write Inhibit	X	X	H	—
Standby	H	X	X	High Z

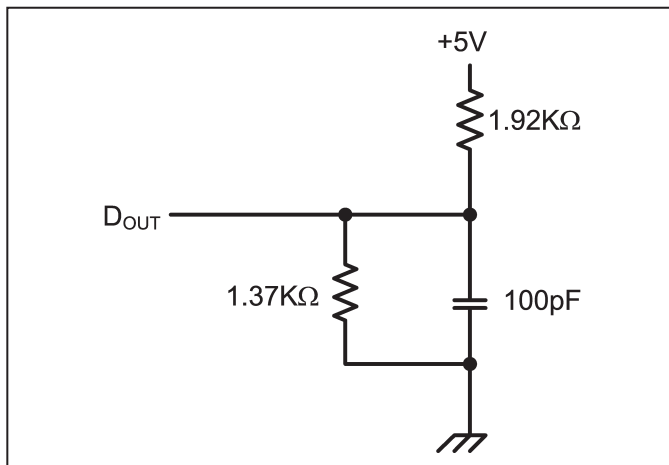
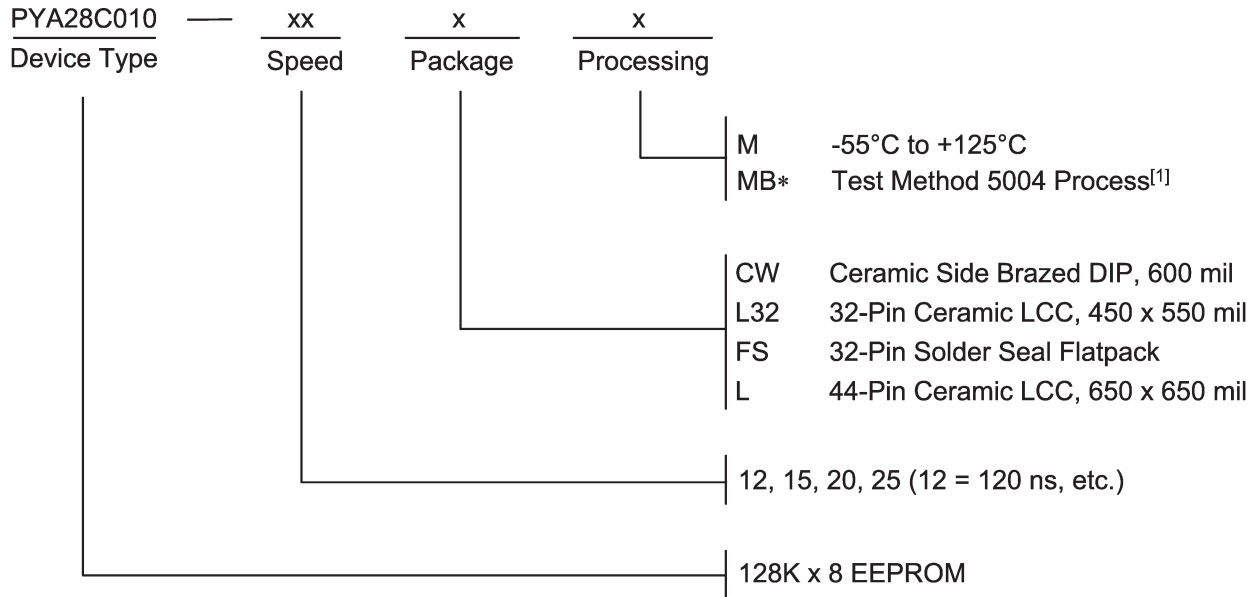


Figure 1. Output Load



## ORDERING INFORMATION

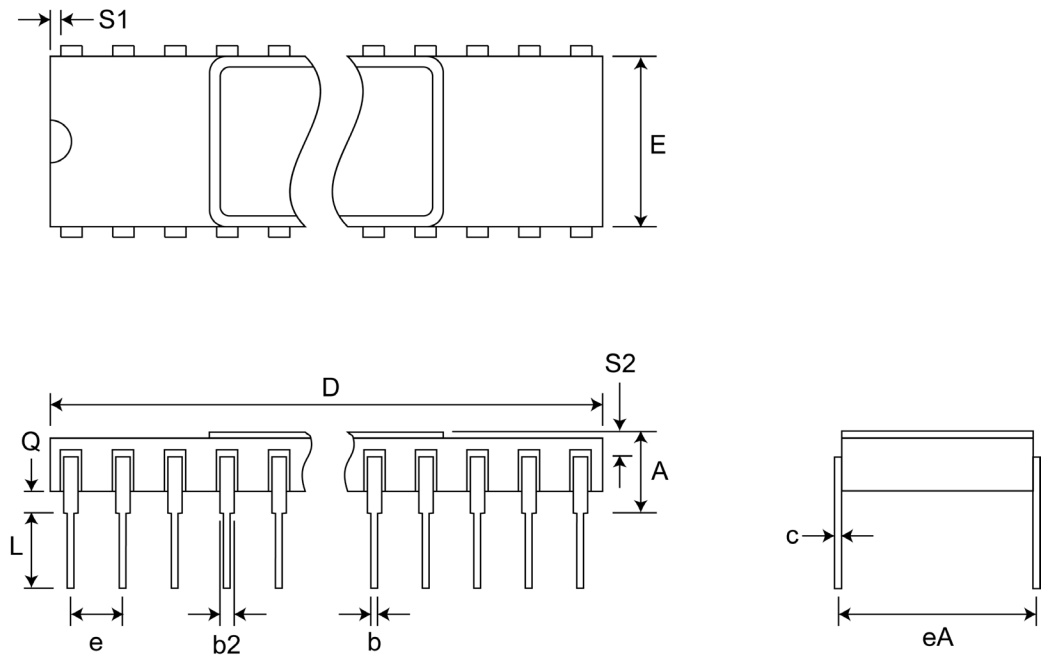


[1] Parts are not MIL-STD-883 compliant. Parts are processed per Test Method 5004.



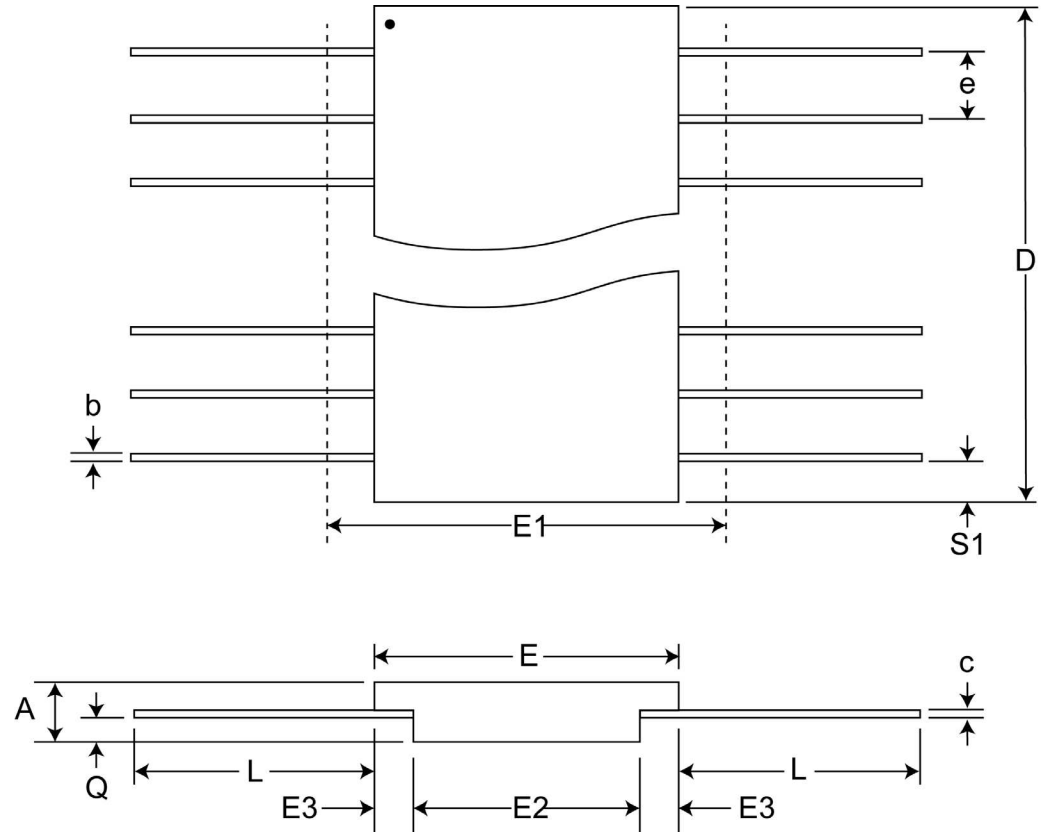
Pkg #	C10	
# Pins	32 (600 mil)	
Symbol	Min	Max
A	-	0.225
b	0.014	0.026
b2	0.045	0.065
C	0.008	0.018
D	-	1.680
E	0.510	0.620
eA	0.600 BSC	
e	0.100 BSC	
L	0.125	0.200
Q	0.015	0.070
S1	0.005	-
S2	0.005	-

**SIDE BRAZED DUAL IN-LINE PACKAGE (600 mils)**



Pkg #	FS-3	
# Pins	32	
Symbol	Min	Max
A	0.097	0.125
b	0.015	0.019
c	0.003	0.009
D	-	0.830
E	0.400	0.420
E1	-	0.450
E2	0.180	-
E3	0.030	-
e	0.050 BSC	
L	0.250	0.370
Q	0.020	0.045
S	-	0.045
S1	0.000	-
M	-	0.002
N	32	

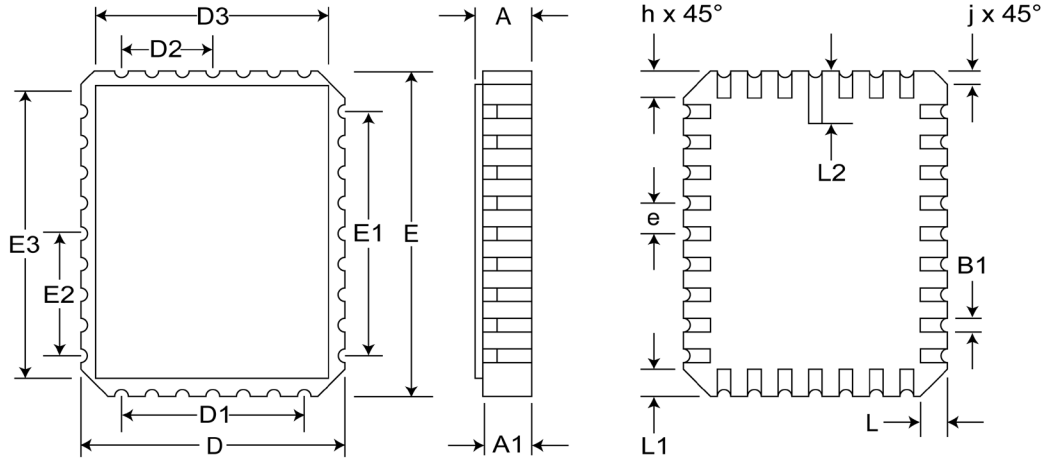
**SOLDER SEAL FLAT PACKAGE**





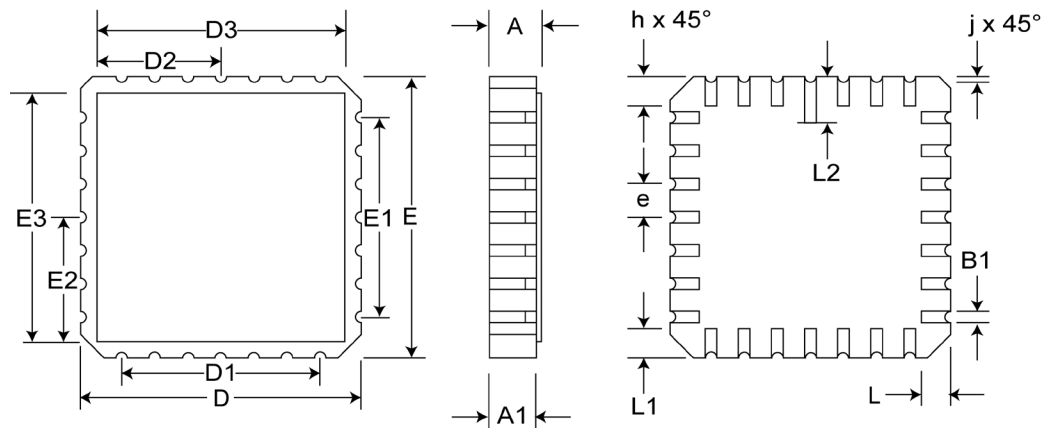
### RECTANGULAR LEADLESS CHIP CARRIER

Pkg #	<b>L6</b>	
# Pins	32	
Symbol	Min	Max
A	0.060	0.075
A1	0.050	0.065
B1	0.022	0.028
D	0.442	0.458
D1	0.300 BSC	
D2	0.150 BSC	
D3	-	0.458
E	0.540	0.560
E1	0.400 BSC	
E2	0.200 BSC	
E3	-	0.558
e	0.050 BSC	
h	0.040 REF	
j	0.020 REF	
L	0.045	0.055
L1	0.045	0.055
L2	0.075	0.095
ND	7	
NE	9	



### SQUARE LEADLESS CHIP CARRIER

Pkg #	<b>L14</b>	
# Pins	44	
Symbol	Min	Max
A	0.070	0.088
A1	0.060	0.075
B1	0.022	0.028
D/E	0.640	0.660
D1/E1	0.500 BSC	
D2/E2	0.250 BSC	
D3/E3	-	0.662
e	0.050 BSC	
h	0.040 REF	
j	0.020 REF	
L	0.045	0.055
L1	0.045	0.055
L2	0.080	0.090
ND	11	
NE	11	



**REVISIONS**

<b>DOCUMENT NUMBER</b>	EEPROM103
<b>DOCUMENT TITLE</b>	PYA28C010 - 128K x 8 EEPROM

<b>REV</b>	<b>ISSUE DATE</b>	<b>ORIGINATOR</b>	<b>DESCRIPTION OF CHANGE</b>
OR	Oct 2009	JDB	New Data Sheet
01	Jun 2011	JDB	Part number corrected throughout from "PYX28C010" to "PYA28C010"
02	Oct 2011	JDB	Added 32-pin flatpack and 44-pin LCC packages